

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
712	205	3/22/2006	BPG

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	3/22/2006	BPG
NPL Search, IEEE Xplore & Citeseer	3/22/2006	BPG